

<b>Notice of References Cited</b>	Application/Control No. 09/918,531	Applicant(s)/Patent Under Reexamination HAYASHI ET AL.	
	Examiner Feben M. Haile	Art Unit 2663	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0043786 A1	03-2003	Kall et al.	370/352
	B	US-2004/0264463 A1	12-2004	Fukushima et al.	370/390
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
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**FOREIGN PATENT DOCUMENTS**

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